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•	BRS	Hits 207	Search Text semiconductor and characteristic and fabricate and substrate and classify\$3		2005/05/31 08:24	Comments	or berny Errors	S1
- 2	BRS	692	mahalanobis	US-PGPUB; USPAT	2005/05/31 08:24			 S2
3	BRS	 	 S1 and S2	US-PGPUB; USPAT	2005/05/31 08:24			s3
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.4	BRS	113	S2 and semiconductor	US-PGPUB; USPAT	08:24			S4
5	BRS	† ₆₁ —	S4 and classify\$3	US-PGPUB; USPAT	2005/05/31 08:25	 		s5
6	BRS	 53 		US-PGPUB; USPAT	2005/05/31 08:25			s 6
7	BRS	50	S6 and distance and compar\$3	US-PGPUB; USPAT	2005/05/31			 S7
8	BRS	47	 S7 and space	US-PGPUB; USPAT	2005/05/31 08:25			S8
9	BRS	6	S8 and fabricate\$3	US-PGPUB; USPAT	2005/05/31 08:28			s9
10	BRS	5310	 semiconductor and classify\$3	US-PGPUB; USPAT	2005/05/31 08:28			S10
11	BRS	32	S10 and test near1 element and substrate	US-PGPUB; USPAT	 2005/05/31 08:32			 S11 ·
12	BRS	 	S11 and mahalanobis	US-PGPUB; USPAT	2005/05/31 08:51			 S12
13	BRS	0	mahalanobis and classify\$3 near1 semiconductor	US-PGPUB; USPAT	2005/05/31 08:52			 S13
14	BRS	1113	mahalanobis and semiconductor	US-PGPUB; USPAT	2005/05/31 08:52			 S14
15	BRS	749103	14a dn fabricat\$3	US-PGPUB; USPAT	2005/05/31 08:53			S15
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	<u> </u>	us	20050210	40	Method and apparatus for	156/345.15	+ +	Shekel, Yehuda et	-
		20050028932		1	real-time dynamic chemical analysis			al.	
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	+	. us — —	20041118	19	Analysis method for	365/202		Kadota, Kenichi	-
	1	20040228186 A1	1	1	semiconductor device.	1	İ	<u>.</u>	
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	7	us	20041104	56	Methods of detecting	435/6	435/287.2	Dickinson, Todd et	
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1	7	us —	20030327	18	Pattern evaluation	382/145	382/192	Mitsui, Tadashi	
	1	20030059104 A1			system, pattern evaluation method and	į	ļ		11111
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1	\neg	US	20021219	28	Apparatus for diagnosing failure in equipment	700/21	700/17; 700/79;	Ushiku, Yukihiro	
	1	20020193891 A1		1	using signals relating t	0	700/80;	!	
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	7	US 20020156549	20021024	22	Controlling method for manufacturing process	700/108	700/111; 700/116;	Hayashi, Shunji	
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4	-		20020801	152	Alternative substrates	435/6	435/287.2	Dickinson, Todd et	-!!-
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4	7	US 6862484	20050301	22	Controlling method for	700/73	1700/110;	Hayashi; Shunji	- -, -
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ל בי	r	- -	E	IS 6782348	20040824	1	Apparatus for diagnosing failure in equipment using signals relating to the equipment	702/183	700/121; 702/185; 702/33; 702/34; 702/35; 702/57; 702/58;	 - 	Ushiku; Yukihiro	
13	Г	- - - - - -	E	JS 6770441 32	20040803	53	Array compositions and methods of making same	435/6	714/48 422/102; 422/68.1; 435/283.1; 435/287.2; 435/287.8; 435/288.2; 435/288.3;		Dickinson; Todd et al.	
14		- -		35 6741341 32	20040525	1	Reentry vehicle Reentry vehicle Reference with IR and Reference variable FOV laser radar	356/141.1	435/288.4; 435/288.5; 435/7.1 250/203.6; 250/342; 356/139.04; 356/139.07; 356/4.01		DeFlumere; Michael E.	
15	ſ	_ _ -		JS 6629090 32	20030930	43	method and device for analyzing data	706/47	 		Tsuda; Hidetaka et al.	
16	r		F	JS 6529276 31	 - 20030304	42	Optical computational system	356/419	 356/310; 356/330; 706/40	 	Myrick; Michael L.	
17	ſ		İ	us 5757001 A	19980526	 	Detection of counterfeit currency	250/339.11	1250/339.09; 250/341.8		Burns; Donald A.	
18				ys 4975581 A	19901204		Method of and apparatus for determining the similarity of a biological analyte from a model constructed from known biological fluids			 <u>-</u> _ <u>-</u> -	Robinson; Mark R. e al.	
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